

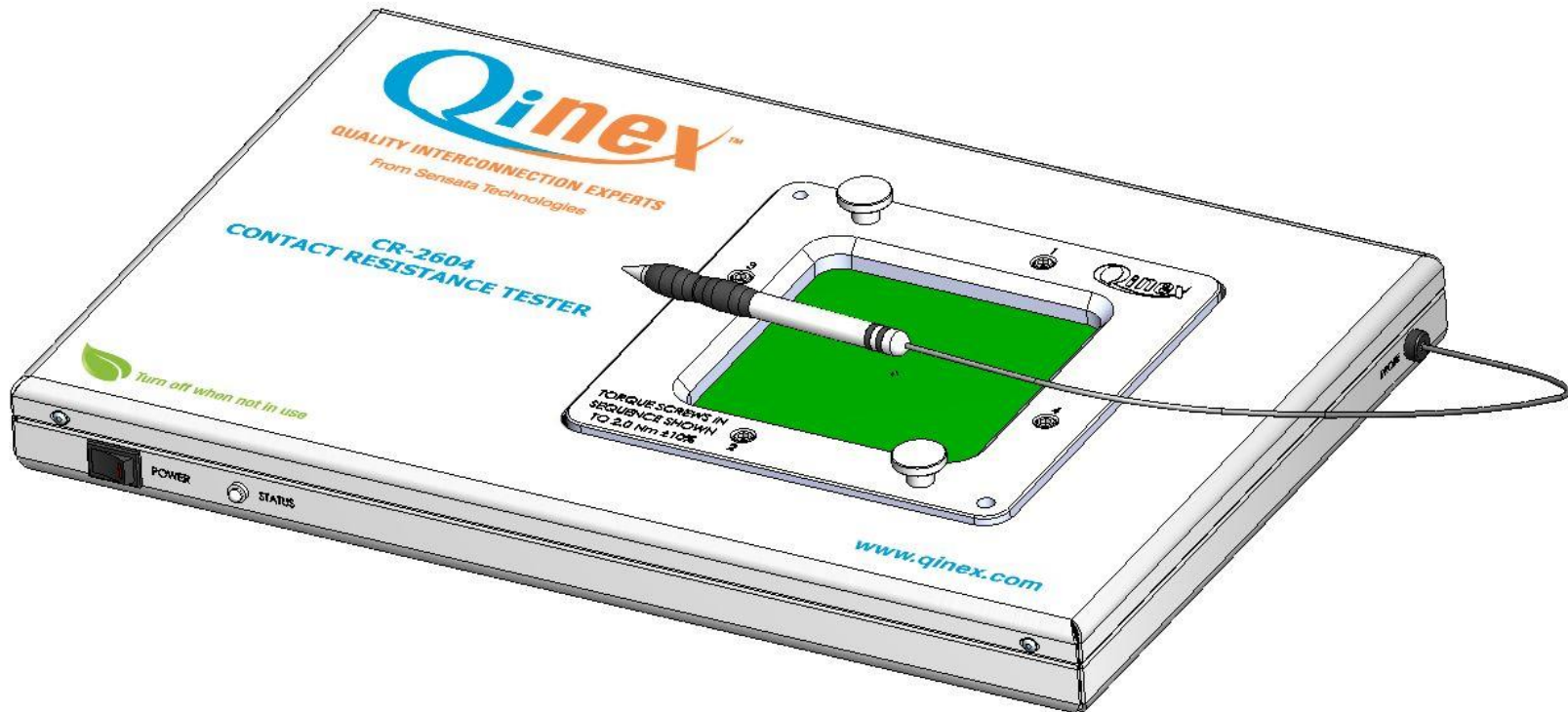


Sensata
Technologies

Automated Contact Resistance Tester CR-2604

The World Depends on Sensors and Controls

What's New



What's New

- Summary of Software Improvements:
 - Improved CRESHost V1.3.9
 - Print/Save image support for Win7
 - Added view of diagnostic log file
 - Support Win7 USB connection at power up
 - Improved verification file format for easier PASS/FAIL display
 - Improvements made for better reliable USB connectivity with CRESHost V1.3.9
 - Software adjustment to incorporate the revision change on microprocessor within CR tester.

CR-260X Users



CR-2604 Payback Periods Customer Example

● Production Use

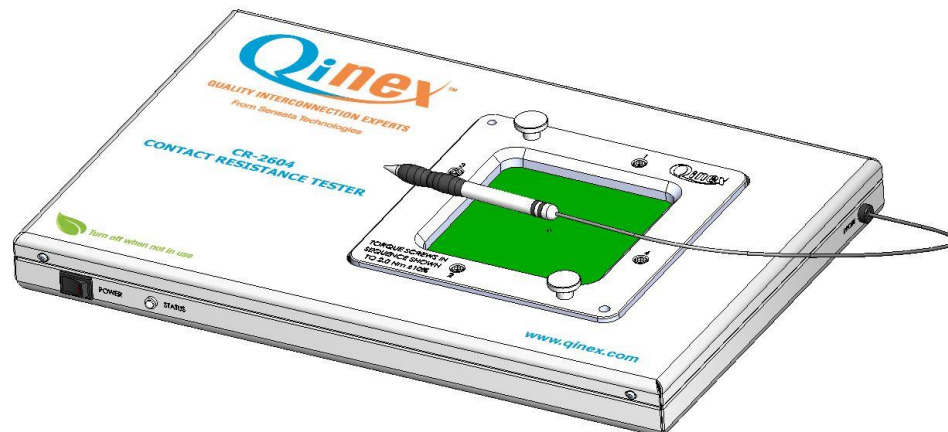
- Customer utilizes CR-2604 to avoid throwing out good pins
- Customer uses 385,693 pins per quarter at average cost of \$1.89 each
- Customer saves average of ~10% Pins that were previously thrown away
- **1 month Payback period**

● Lab Use

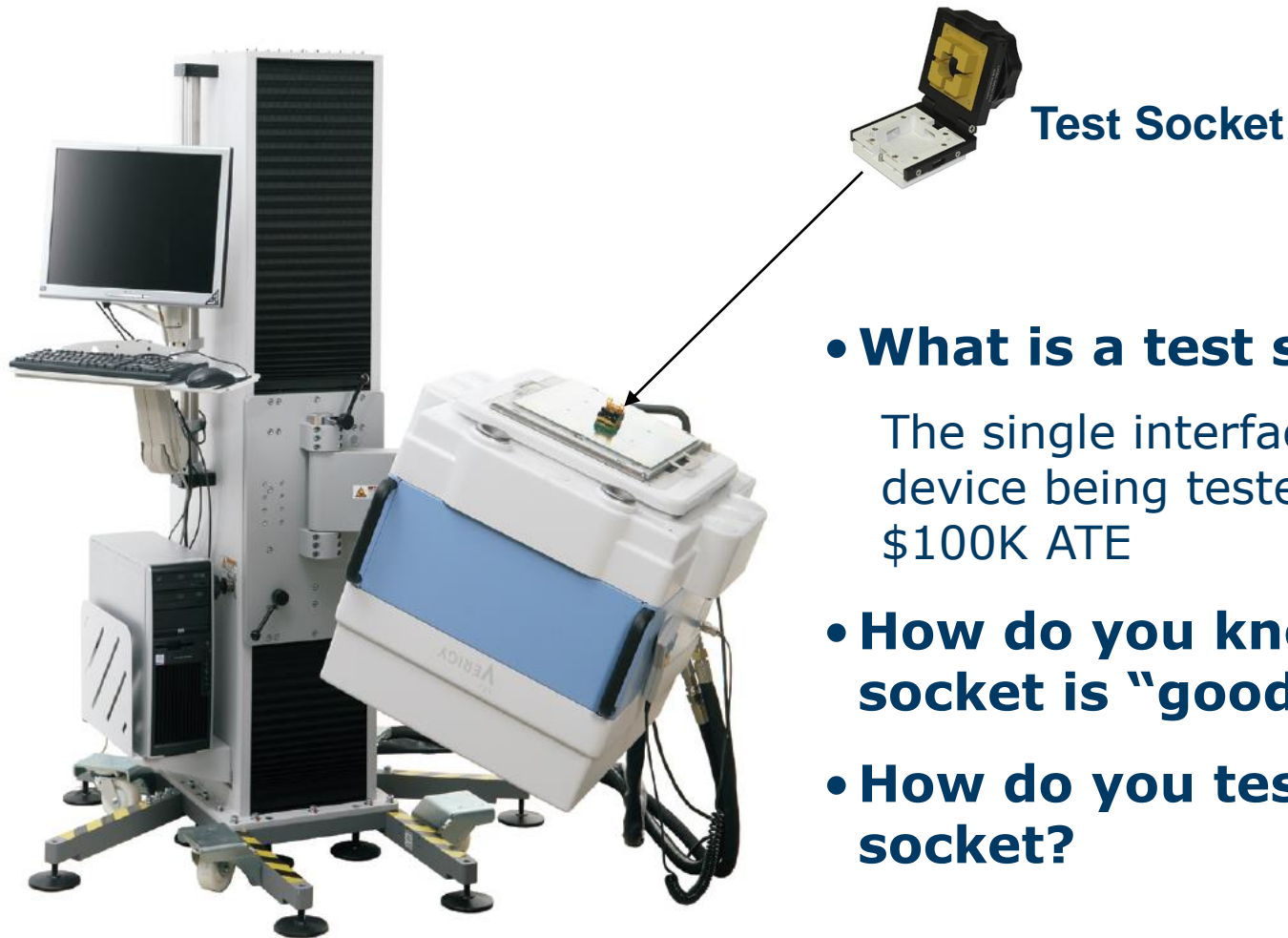
- Customer utilizes CR-2604 on a project basis
- Cost savings derived from savings of Tester & Engineering time = \$3000 per project
- **9 project Payback Period (<1.5 years)**

CR-2604 Contact Resistance Tester

- **Incoming Socket Inspection**
- **Routine Socket Performance Verification**
- **Pin Resistance/Opens**
- **Pin Shorting**
- **Socket Preventative Maintenance**



Introduction



- **What is a test socket?**

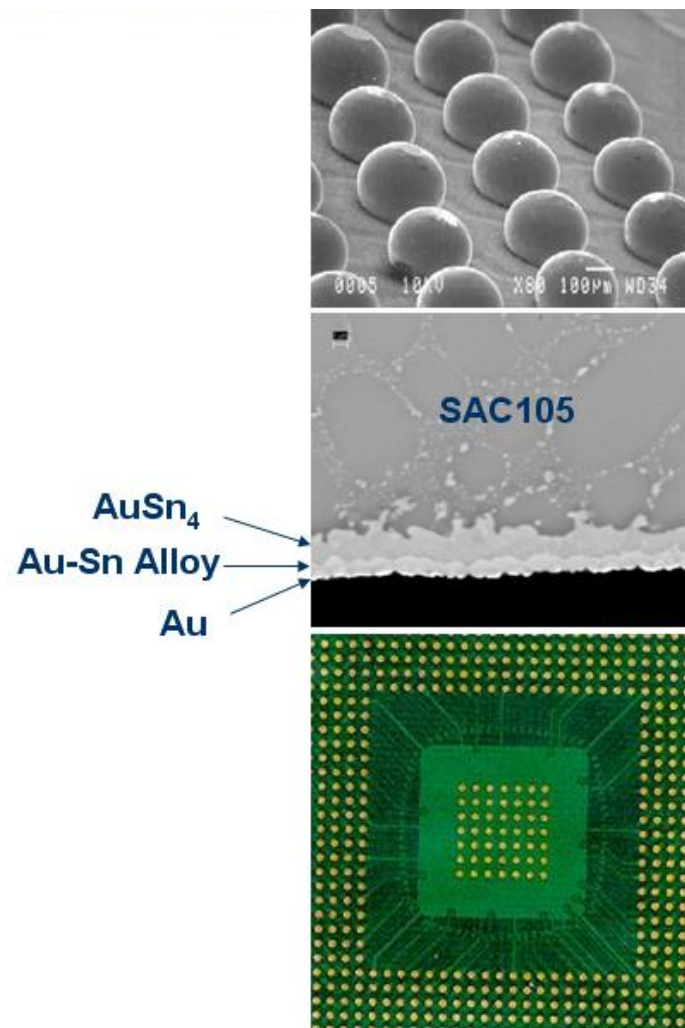
The single interface between a device being tested and a > \$100K ATE

- **How do you know the test socket is "good"?**

- **How do you test a test socket?**

Introduction – Industry Conditions

- **Decreasing Pitches**
 - 1.27mm 1mm 0.8mm
0.5mm 0.4mm ...
 - Smaller pitches require new and more complex socket probe designs.
- **RoHS Directive**
 - The proliferation of solder ball compositions such as SAC105, SAC305 and SAC405 lead to new contamination problems.
- **Increasing Device I/O Count & Power**
 - Systems on chip are driving up I/O counts.
 - High performance devices are requiring more power.



Introduction – Industry Need

Problem: Inconsistent and unreliable socket performance

Cause: Contamination build-up on socket pins

Why is high contact resistance bad?

- Can cause excessive pin heating
- Limits available power on supply pins

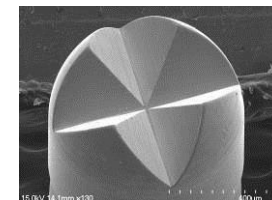
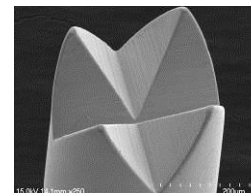
Why is inconsistent contact resistance bad?

- Decreased yield
- Intermittent failures
- Equipment downtime to resolve “problem”
- Difficult to detect and isolate in ATE

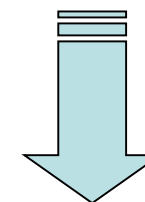
A system is needed to identify failing socket pins before they impact production schedules and yield.

- High contact resistance is an early indicator of failing socket pins caused by wear or contamination
- Sometimes ATE capital equipment can measure this, but the *time is expensive and not flexible*
- Both the contact (spring-loaded pin, elastomer, etc) and the device interface need to be measured

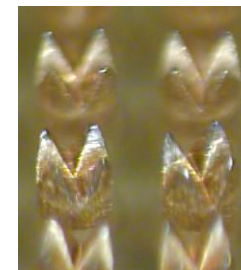
Solution: A device to independently verify a socket’s performance by measuring the resistance of each pin.



Socket Pin With New Pins



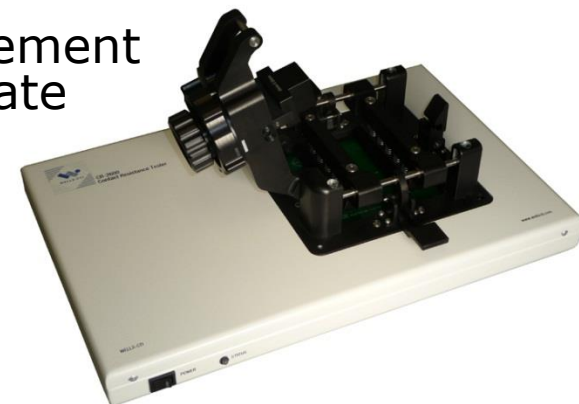
When?
How many cycles?
Which pins?



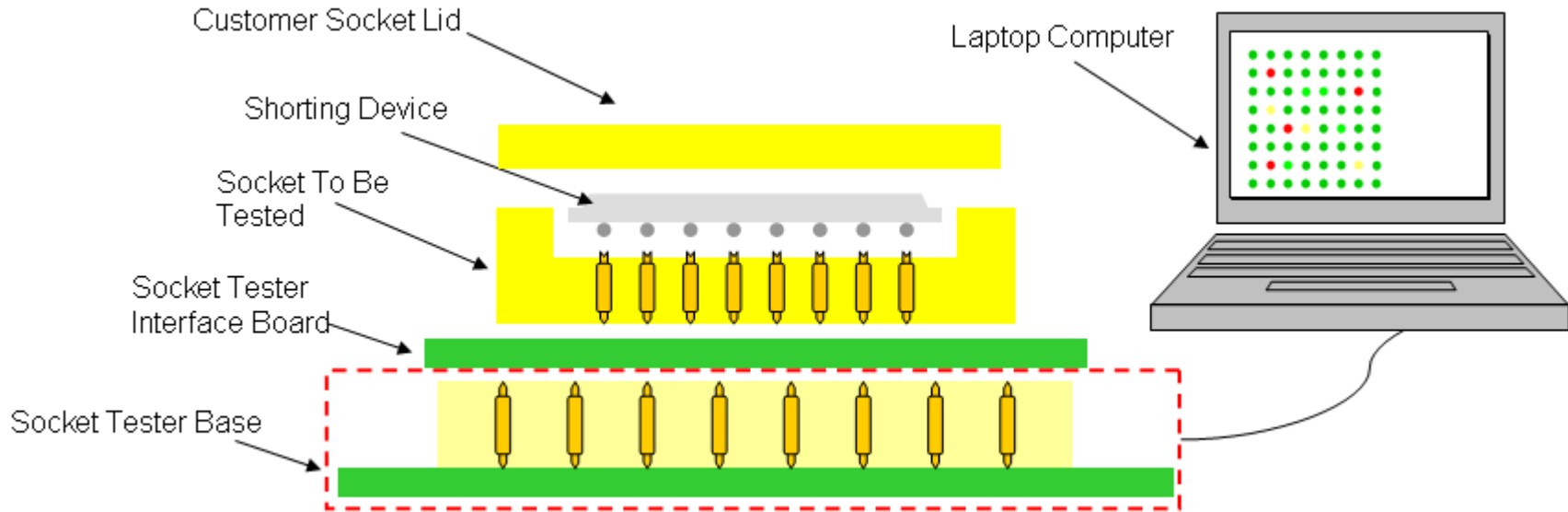
Socket Pin With Contaminated Tips

CR-2604 Socket Contact Resistance Tester

- The CR-2604 tester is a portable, easy to use tool used to validate socket integrity by measuring contact resistance.
- Measure your socket's contact resistance using this PC compatible, lightweight, measuring tool.
- The CR-2604 tester will allow you to identify the locations of open or high resistance pins within your socket array.
- The user interface is displayed on a Windows XP or Windows 7 computer via USB connection.
- No standard maintenance required on tester. The unit has 8 internal low-drift precision 4-Wire resistors for reference. Before each measurement cycle, these resistors are measured to calibrate the measurement circuitry.



Solution Overview

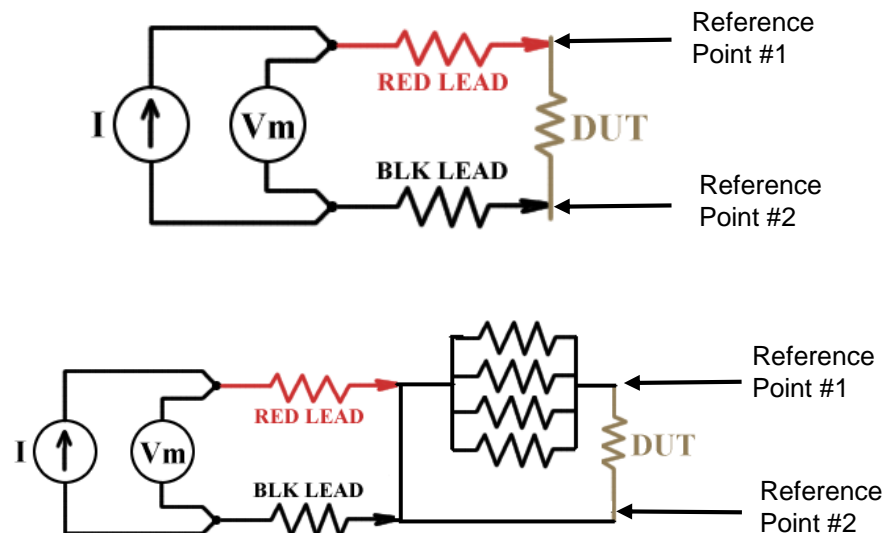
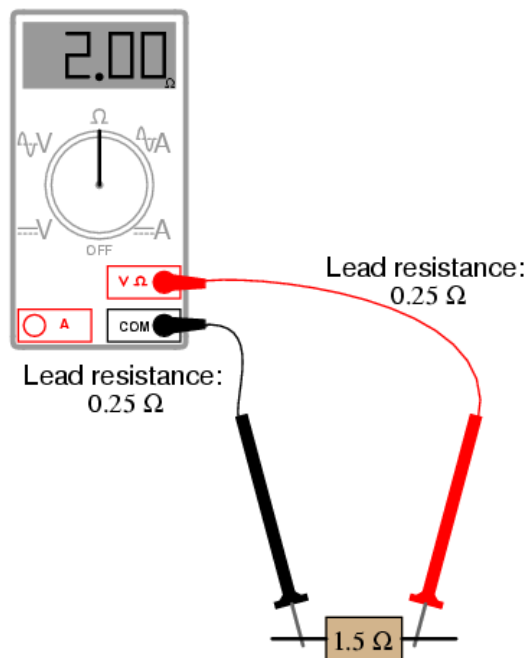


- **Shorting Device:** Shorting/Daisy chain package
- **Socket and Lid:** Spring Probe Socket to be tested
- **Interface Board:** Footprint specific, socket interface card.
- **Socket Tester Base:** Electronic circuitry to perform tester function
- **Host Computer:** Runs Tester software to configure tester and report results

Resistance Measurement Methodology

WORST PIN MEASUREMENT METHOD

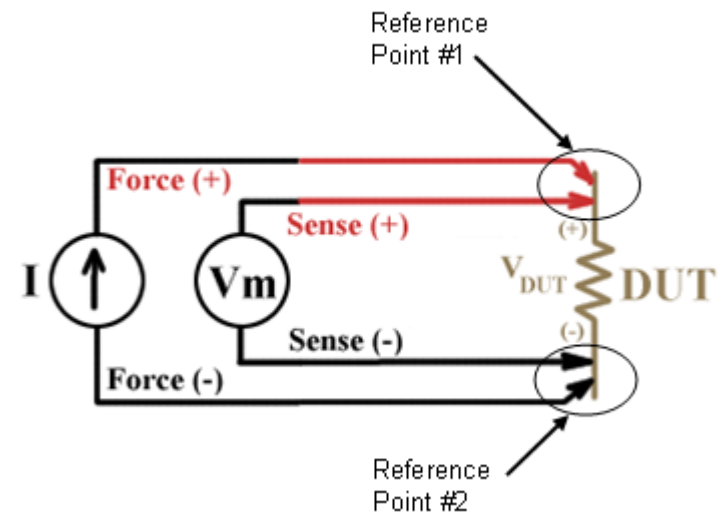
- 2-Wire Standard Approach
 - NOT used by the CR-2604 Tester
 - Measure the DUT resistance plus the test lead resistance
 - Cannot accurately measure low-valued resistors (pins)
 - Typically can only measure Pin pairs plus lead resistance losses (NOT individual Pins)



Resistance Measurement Methodology

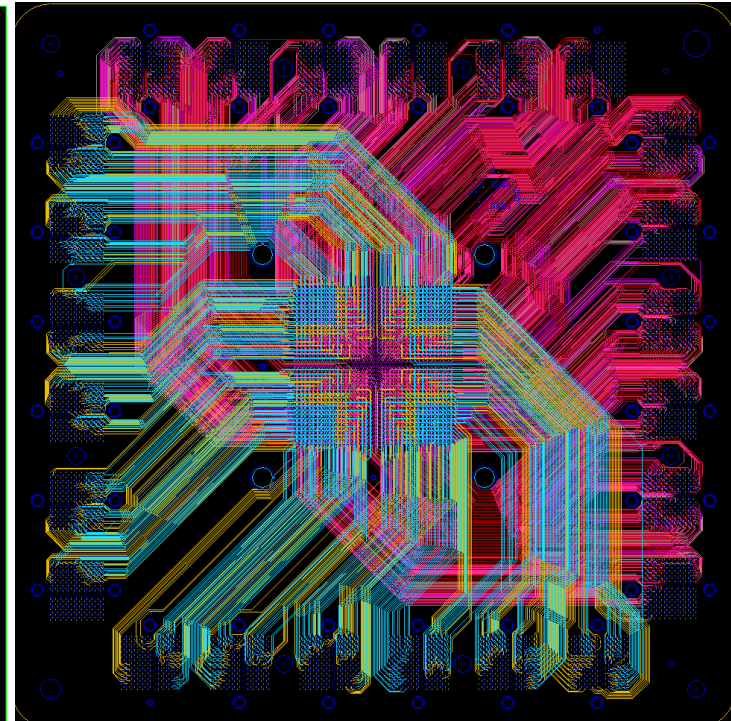
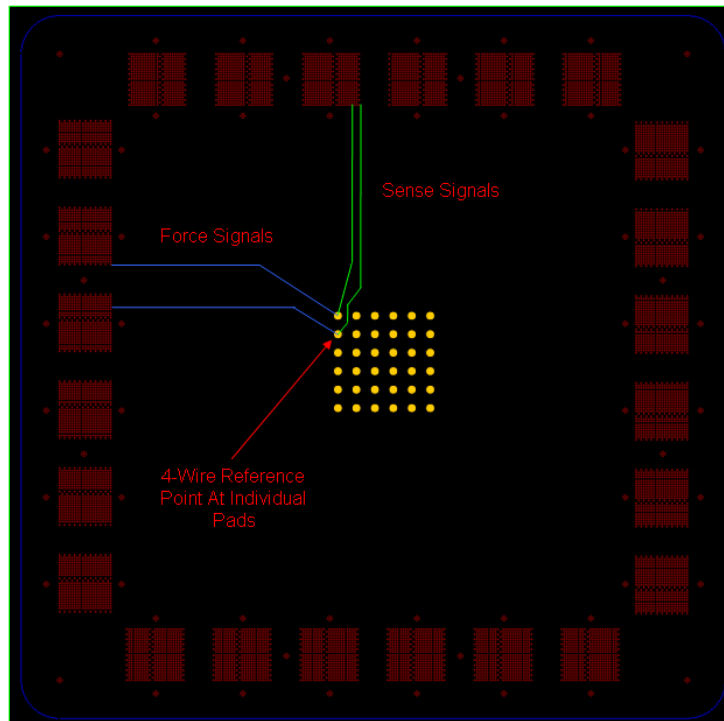
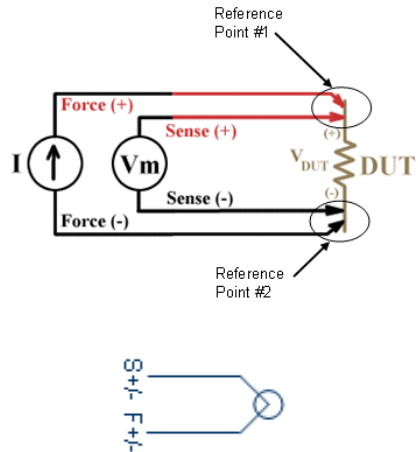
BEST PIN MEASUREMENT METHOD

- 4-Wire (Kelvin) Approach
 - USED by the CR-2604 Tester
 - Eliminates PCB and Cabling From Measurement
 - Requires Separate Current & Voltage Path
 - Accurately measures low-valued resistors
 - Allows for single pin measurement

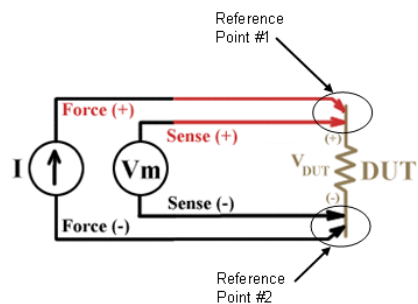


CR-2604 Measures Only the Pin Resistance (no bulk)?

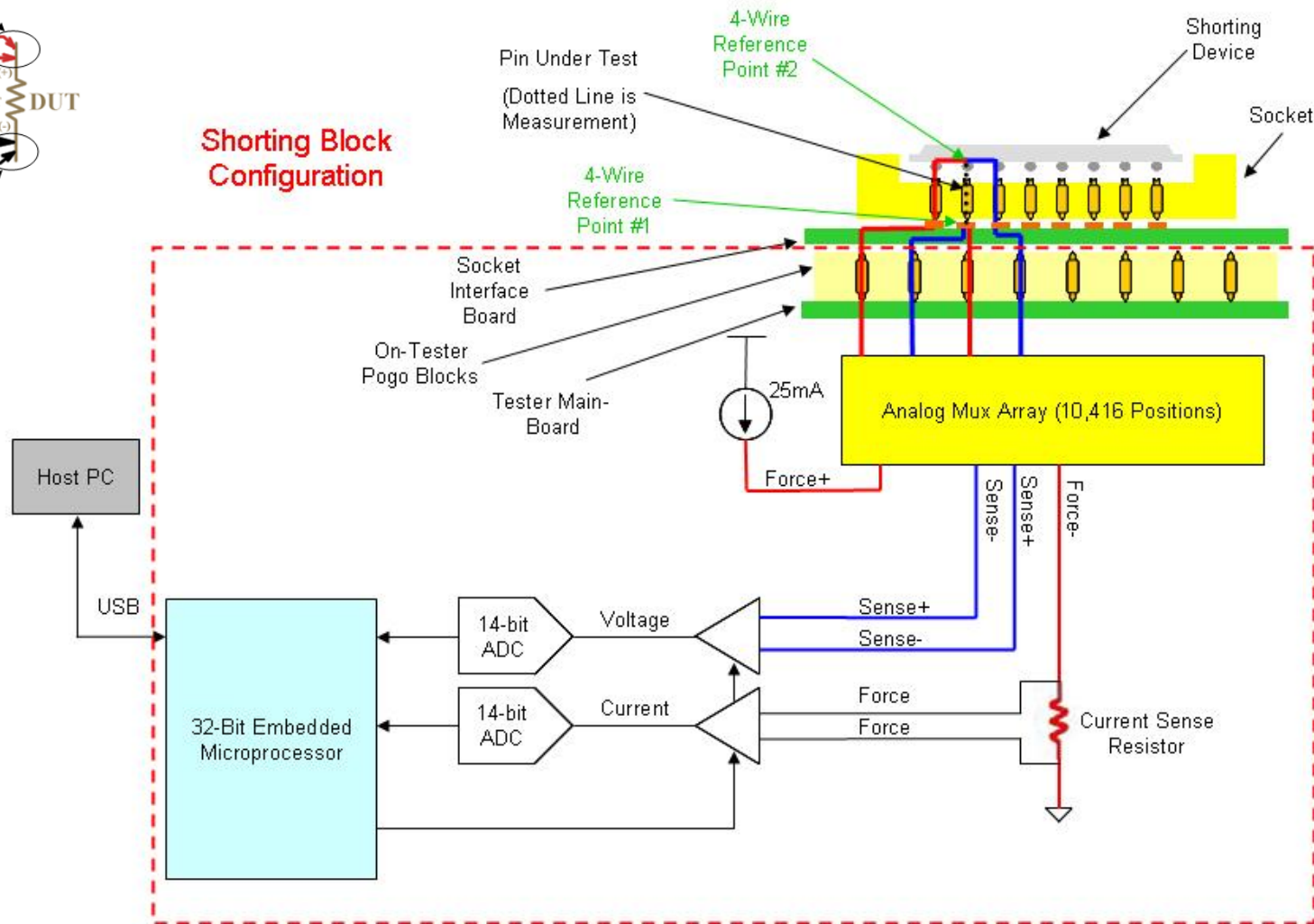
- 4 wire measurements
- Tester interconnects, traces, and switches not included in measurement
- 4-Wire reference at DUT pad



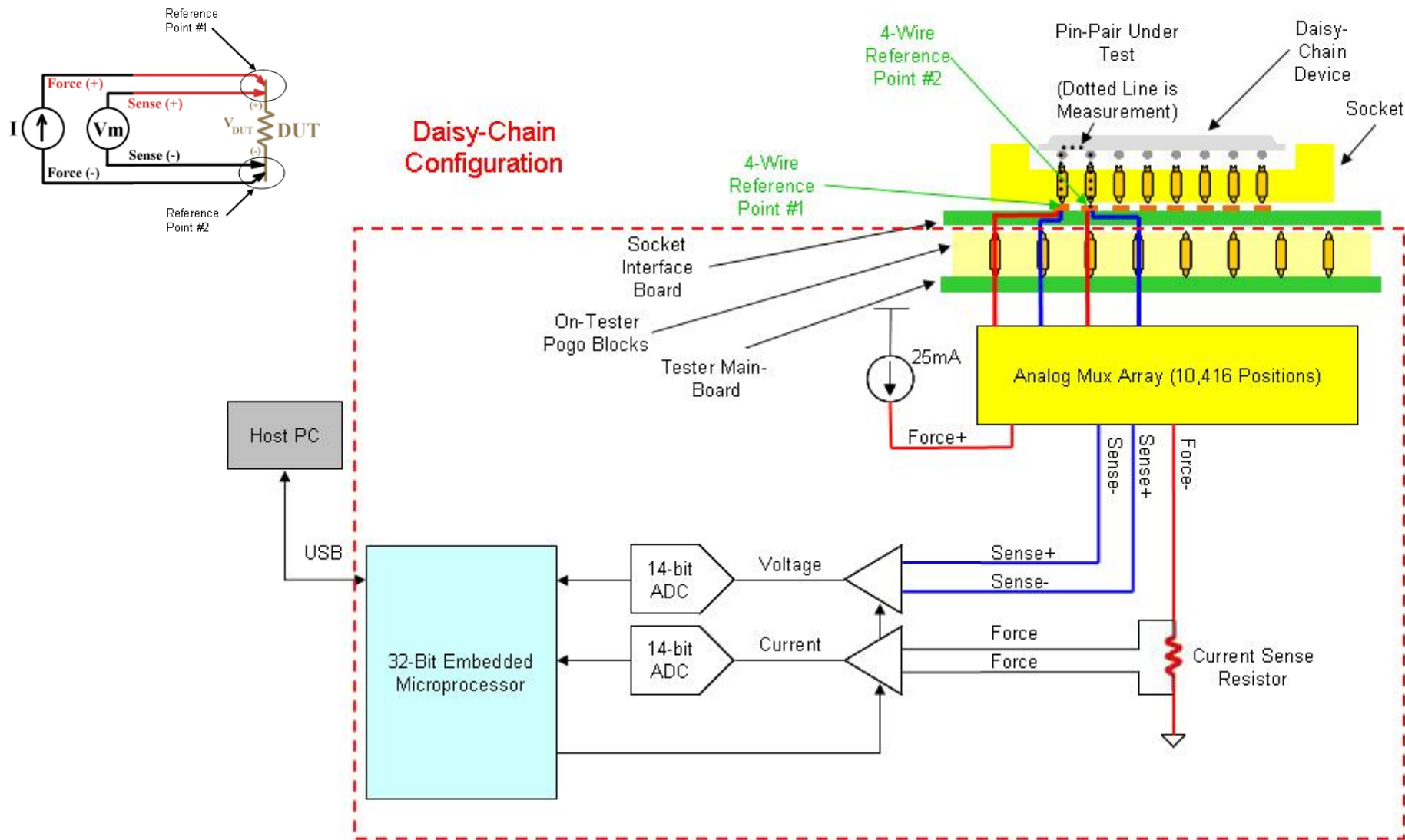
Electrical System Block Diagram Using Shorting Block



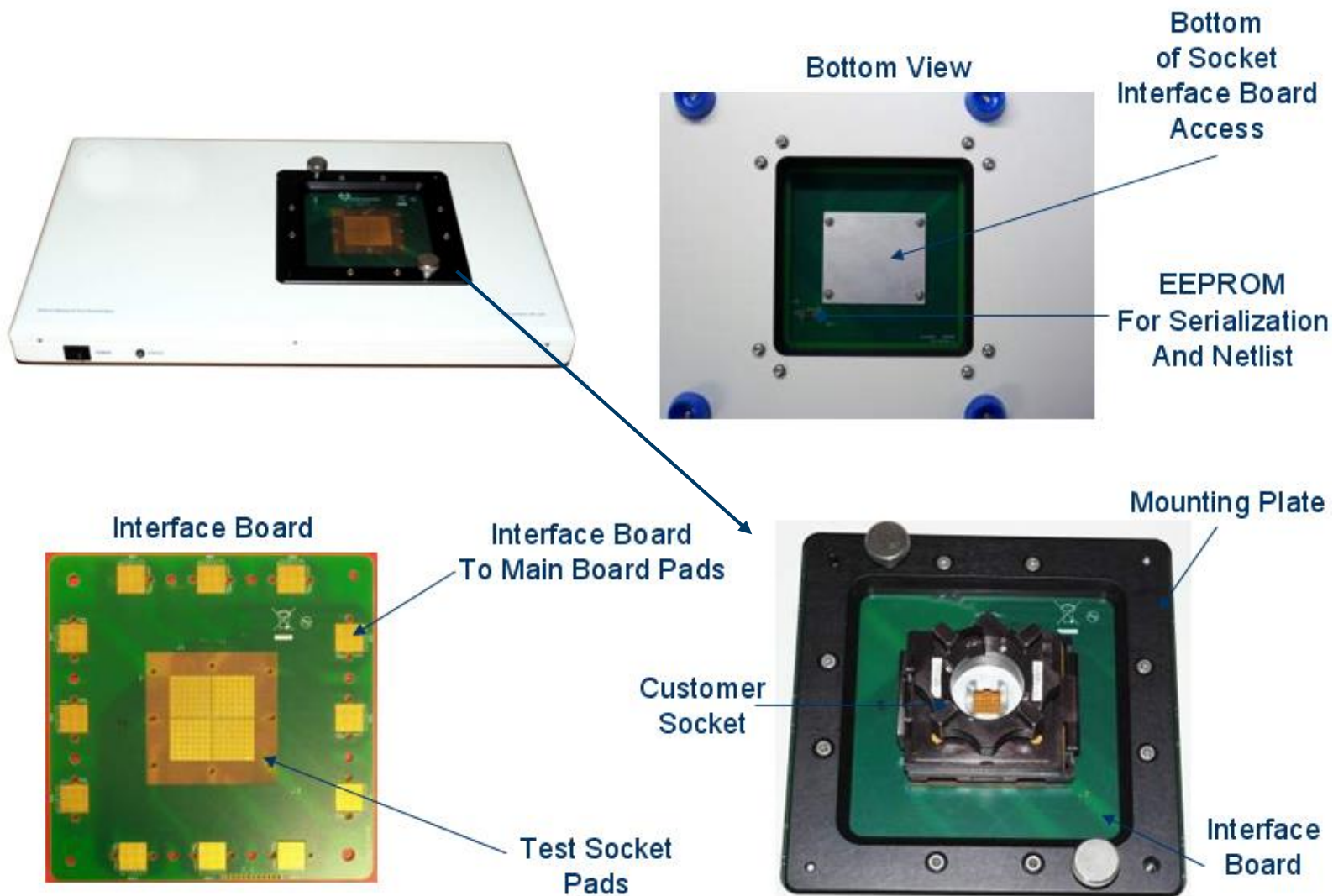
Shorting Block Configuration



Electrical System Block Diagram Using Daisy Chain Device

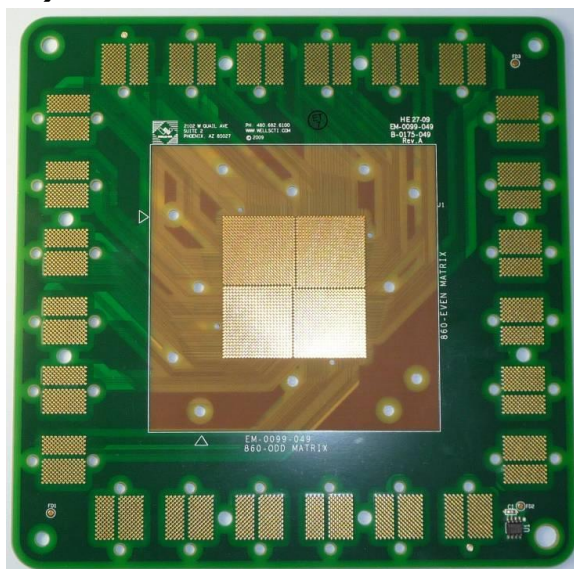


Socket Mounting on Interface Board

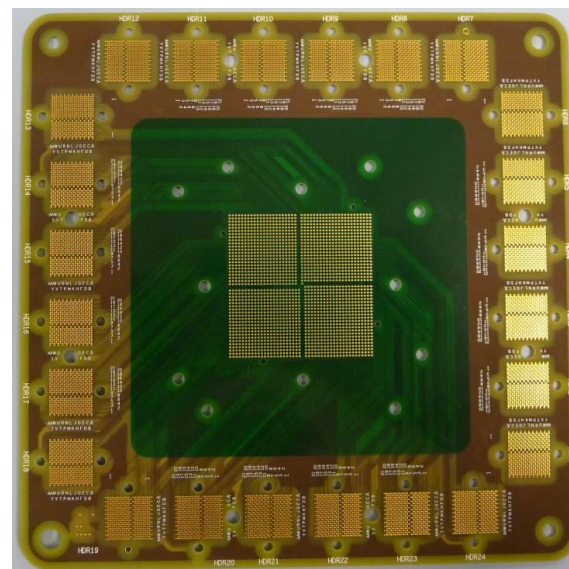


Interface Boards

- The CR-2604 uses interface boards to map a socket footprint to the common tester footprint
- ALL BOARDS PURCHASED FOR USE ON THE CR2600 or CR2601 ARE COMPATIBLE WITH THE CR2604
- Up to 2604 test points (5208 4-Wire traces)
- Interface Board is 7"x7", variable thickness (usually 0.093" – 0.125" thick)



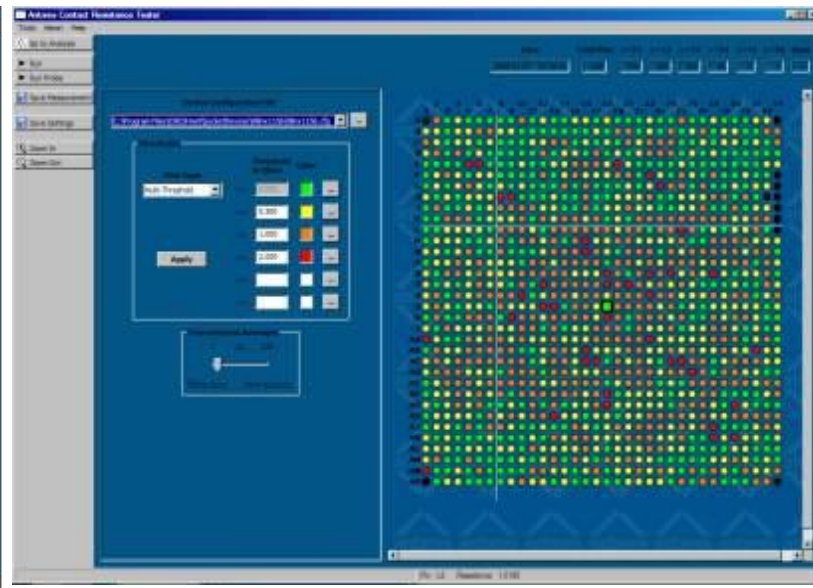
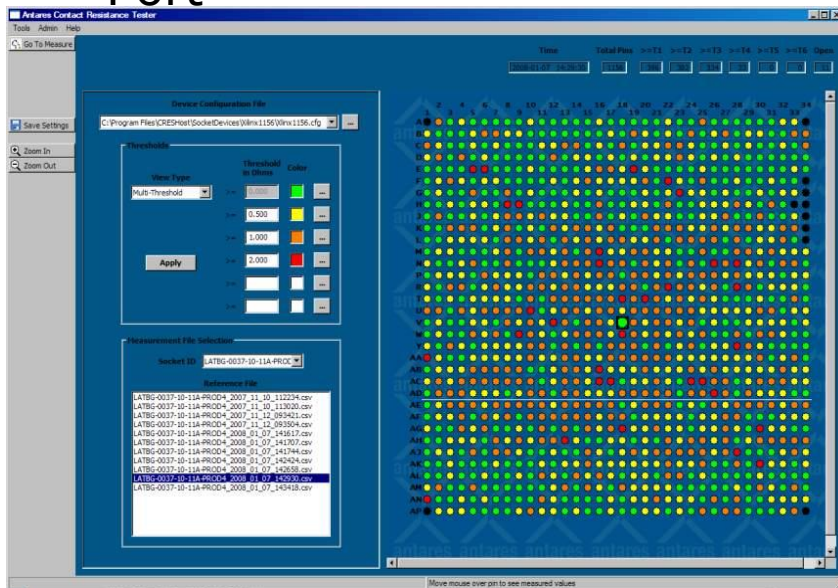
Interface Board Top View



Interface Board Bottom View

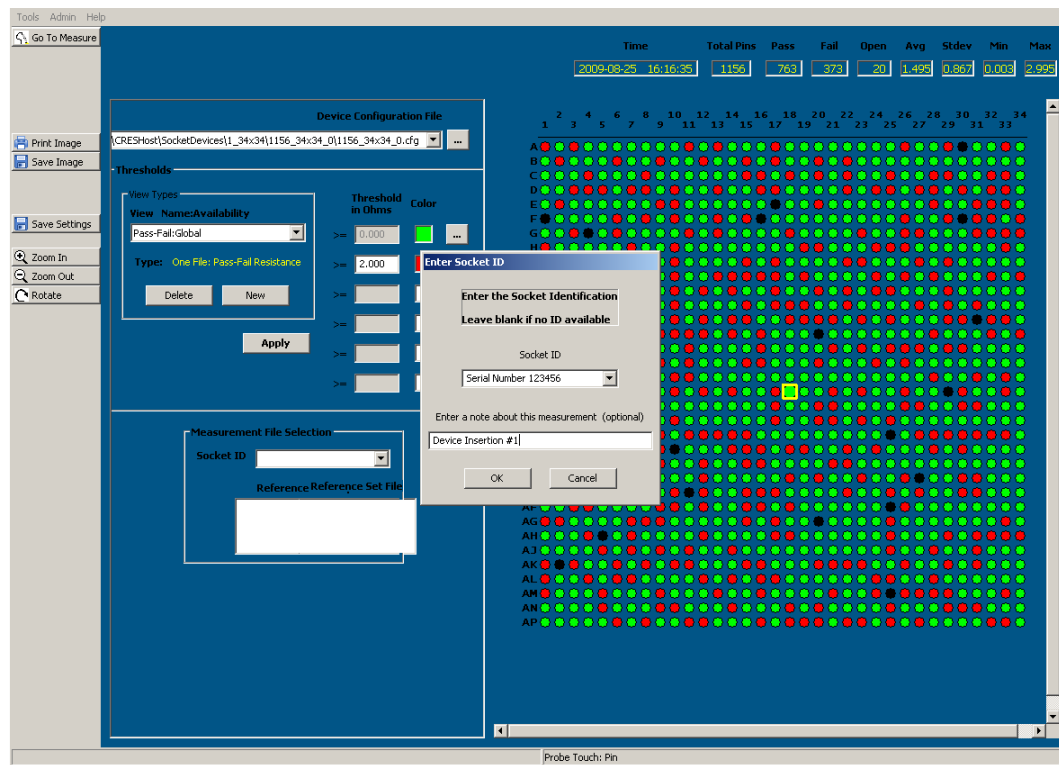
CRES Host Software – User Interface

- Controls CR-2604 tester and allows measured values on all pins to be viewed
- Allows manual saving of socket data for later analysis (CSV Format)
- Compares multiple data sets for trend analysis
- Configurable color-coded resistance thresholds
- Requires Windows XP or Windows 7 computer with Available USB Port



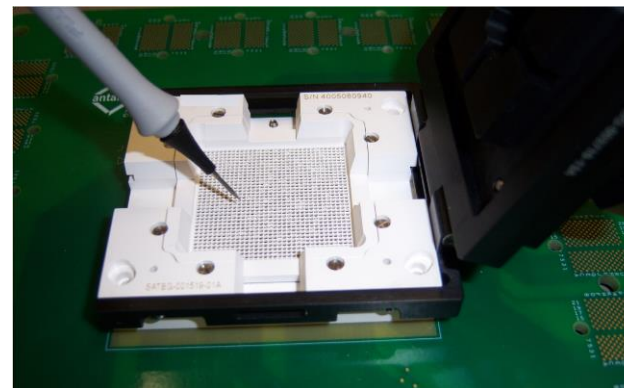
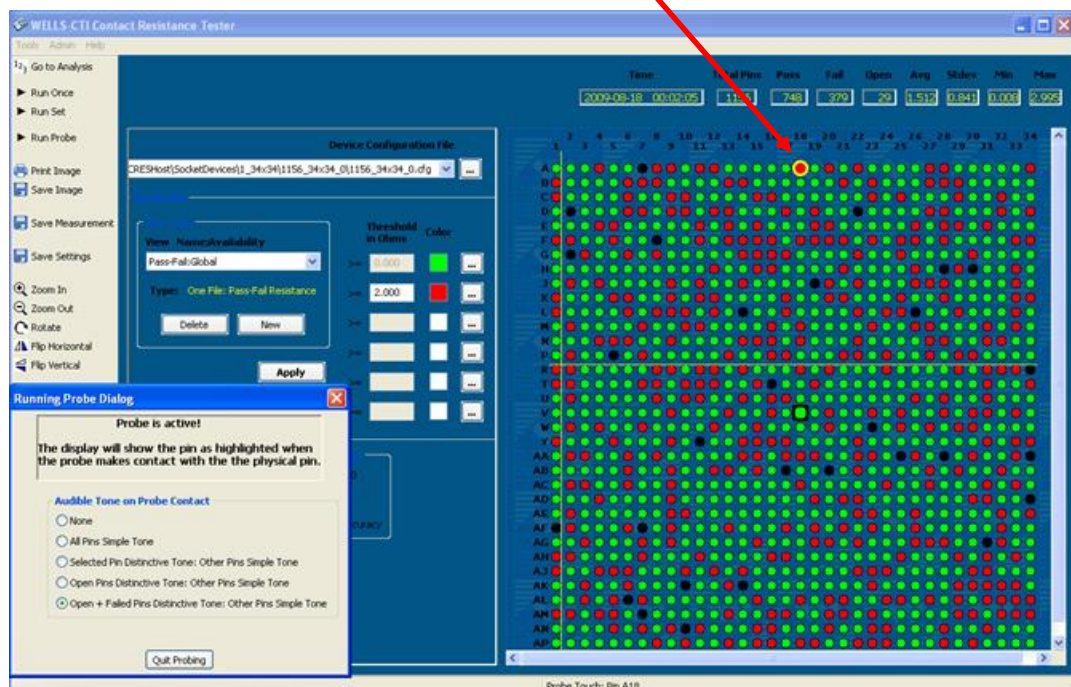
CRES Host Software – User Interface

- Socket Labeling, notes about the test conditions
- Administrator and User modes. Password Protected



Test Probe Pen

- The included handheld test probe allows easy identification of failed pins
- After performing a measurement, probe mode shows the specified pin on the computer screen when it is touched with the test probe pen



CR-2604

Contact Resistance Tester Specifications

- 4-wire pin measurements up to bulk of shorting plate.
- Resistance measurement range: 0 ohms to 300 ohms
- 0.5% or 5 m Ω Overall Accuracy, whichever is greater (using Wells-CTI Verification Board, see slide 24)
- Maximum socket I/O supported 2604 pins
- Force Current \sim 25mA (variable, not adjustable)
- Average Measurement Time : 25 Pins / Second (depending on averaging setting)

Options – Universal Manual Actuator

- Allows socket to be tested without attaching to interface board with screws.
- Enables quick socket changes
- The plunge depth of actuator pressure pad is configurable and repeatable.
- Comes with replaceable pressure pads supporting packages from 10mm to 50mm.

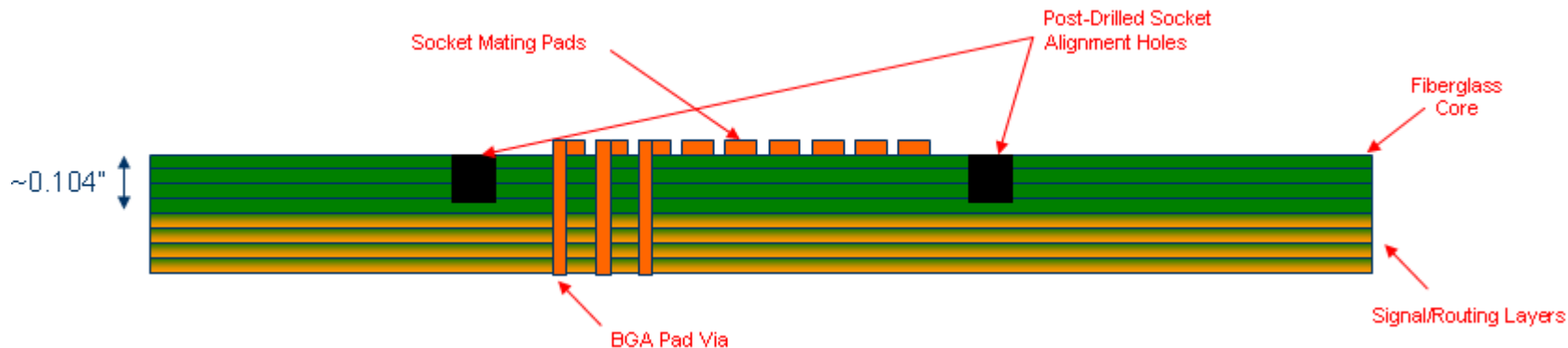


Manual Actuator Video

Options – Universal Interface Boards

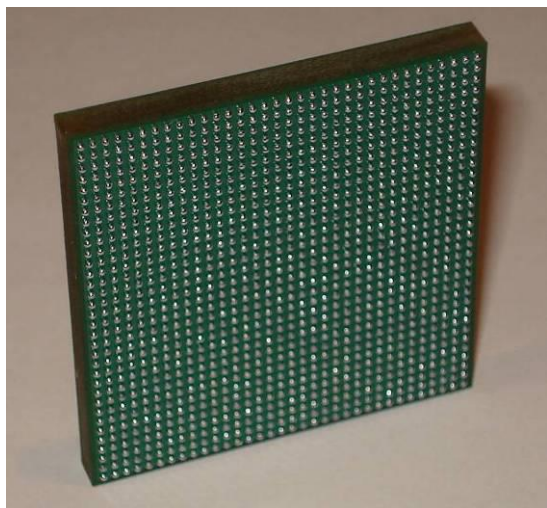
- Requires Universal Manual Actuator Unit.
- Inexpensive quick turn generic interface boards compared to custom designs.
- Quick socket change out when testing multiple sockets.
- Stocked and post-drilled to accommodate socket alignment features
- Can often support multiple socket footprints
- Available for pitches:

Part Number	Pitch	Matrix Size	Pad Size	Max Dowel Pin Length
EM-0099-100	1.27mm	51x51	30 mil	2.54mm
EM-0099-101	1.0mm	51x51	25 mil	2.54mm
EM-0099-102	0.8mm	40x40	17 mil	2.54mm
EM-0099-103	0.65mm	40x40	14.9 mil	2.54mm
EM-0099-104	0.5mm	40x40	12 mil	2.54mm



Options – PCB/BGA Shorting Packages

- BGA shorting packages
- 0.8mm and above pitches available
- Built to customer provided package specification



Advantages

- Ball interface very similar to customer package
- Cost per device is relatively low
- Solder ball compositions
Tin/Lead,
SAC305,
SAC105.

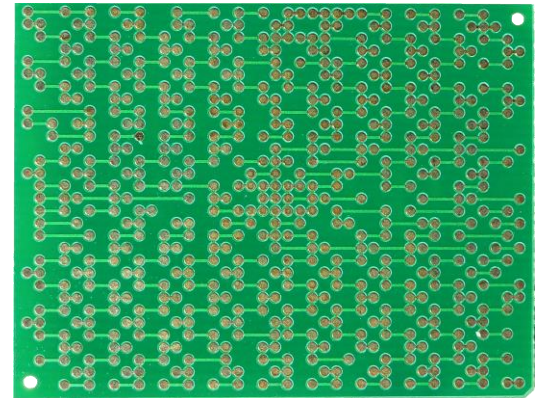
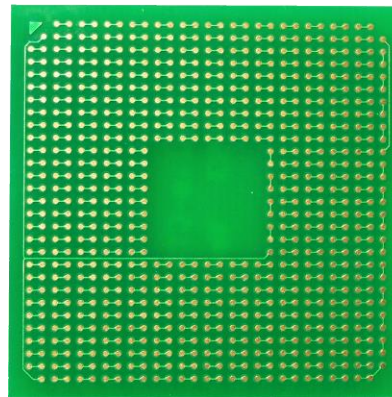
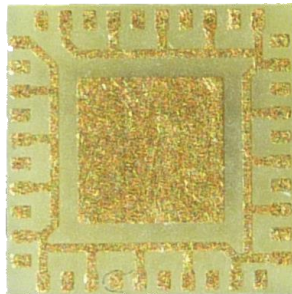
Disadvantages

- Solder balls will wear out (estimated 50-100 insertions)
- Reduced measurement repeatability
- Minimum lot of 25 pieces

Options

LGA/QFN Shorting Packages

- PCB and Machined available
- Various plating options
- Built to customer provided package specification
- **WELLS-CTI recommends Gold plated pads for best repeatability**

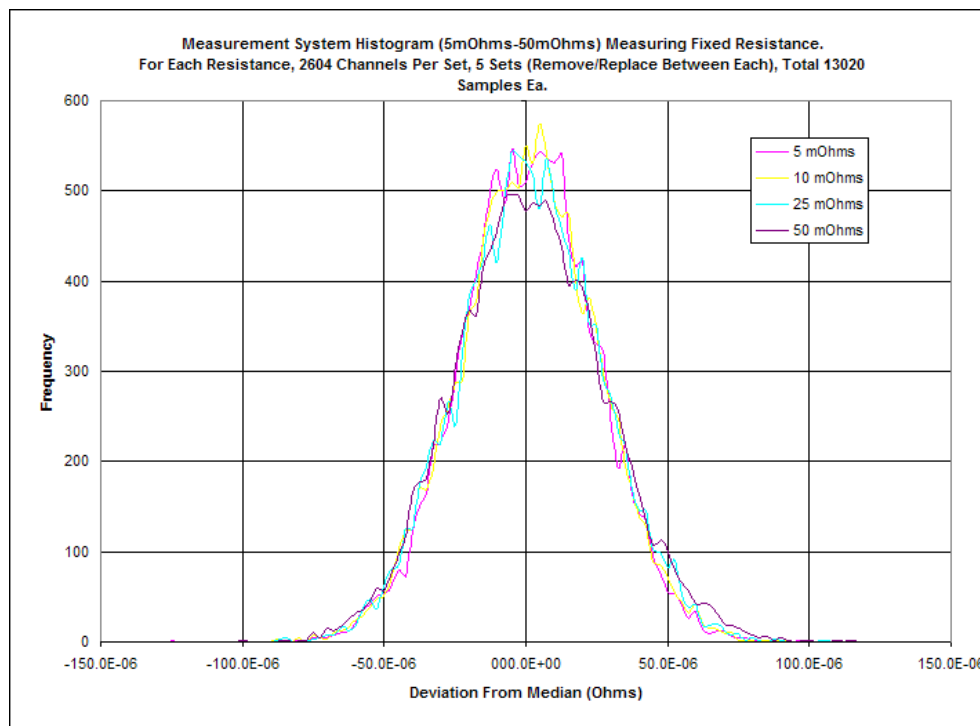


Measurement System Repeatability

- To validate performance we have created verification cards (EM-0125) which are fabricated using commercially available precision resistors
 - The resistors are soldered to the verification card to eliminate any variance due to mechanically cycling the resistors.
- During the verification test each of the channels is used to measure the same resistor providing 2604 data points
- For repeatability verification the board is removed and re-installed and the test repeated. This repeat is performed 5 times producing 5 sets of data. Each data set includes 10,416 measurements
- The validation is conducted with 11 different resistances using different precision resistor boards. The resistor values range from 2.5 m Ω to 60,000 m Ω , or 60 ohms

Measurement System Repeatability

R (mΩ)	σ (μΩ)	6σ (μΩ)
2.5	15.78	94.69
5	23.61	141.68
10	24.18	145.05
25	24.85	149.10
50	26.46	158.76
500	32.72	196.30
1000	33.36	200.15
2000	62.40	374.42
5000	89.08	534.49
10000	229.98	1379.89
60000	1074.41	6446.47



- The results are shown graphically. Note that the resistance values are reported in mili-ohms (mΩ) however the units of the std.dev σ are micro-ohms (μΩ)
- The data shows that:
 - the standard deviation is always less than 1% and, at the resistance of a typical pin, 50 mΩ **the std. dev is .05%.**
 - For 6 σ , which will include **99.9997% of the population, the error is less than 0.5%** at the resistances of interest.